National Semiconductor

March 1993

54ACT/74ACT823
9-Bit D Flip-Flop

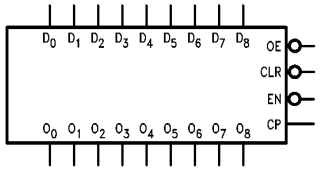
General Description

The 'ACT823 is a 9-bit buffered register. It features Clock Enable and Clear which are ideal for parity bus interfacing in high performance microprogramming systems. The 'ACT823 offers noninverting outputs and is fully compatible with AMD's Am29823.

Features

- Outputs source/sink 24 mA
- TRI-STATE® outputs for bus interfacing
- Inputs and outputs are on opposite sides
- 'ACT823 has TTL-compatible inputs

Logic Symbols



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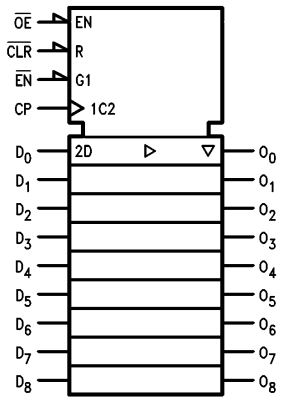
IEEE/IEC



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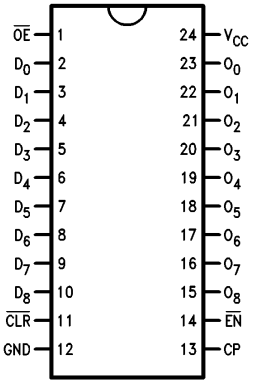
Connection Diagrams

Pin Assignment for DIP, Flatpak and SOIC



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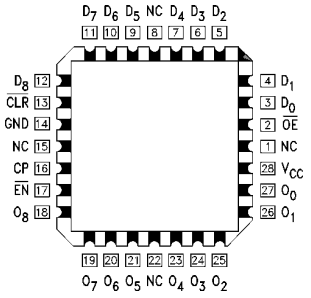
Pin Assignment for LCC



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Pin Names	Description
D_0–D_8	Data Inputs
O_0–O_8	Data Outputs
$\overline{OE}$	Output Enable
$\overline{CLR}$	Clear
CP	Clock Input
$\overline{EN}$	Clock Enable

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Functional Description

The 'ACT823 consists of nine D-type edge-triggered flip-flops. These have TRI-STATE outputs for bus systems organized with inputs and outputs on opposite sides. The buffered clock (CP) and buffered Output Enable ($\overline{OE}$) are common to all flip-flops. The flip-flops will store the state of their individual D inputs that meet the setup and hold time requirements on the LOW-to-HIGH CP transition. With $\overline{OE}$ LOW, the contents of the flip-flops are available at the outputs. When $\overline{OE}$ is HIGH, the outputs go to the high impedance state. Operation of the $\overline{OE}$ input does not affect the state of the flip-flops. In addition to the Clock and Output Enable pins, there are Clear ($\overline{CLR}$) and Clock Enable ($\overline{EN}$) pins. These devices are ideal for parity bus interfacing in high performance systems.

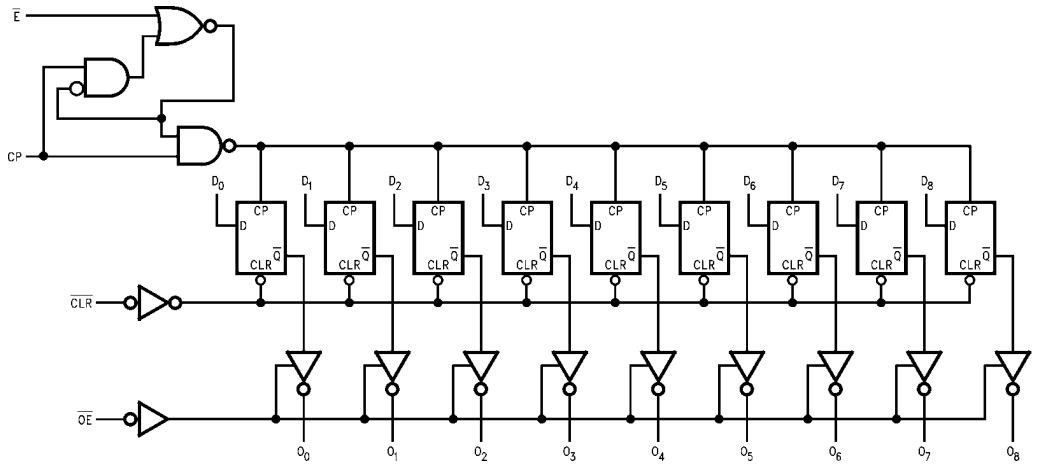
When $\overline{CLR}$ is LOW and $\overline{OE}$ is LOW, the outputs are LOW. When $\overline{CLR}$ is HIGH, data can be entered into the flip-flops. When $\overline{EN}$ is LOW, data on the inputs is transferred to the outputs on the LOW-to-HIGH clock transition. When the $\overline{EN}$ is HIGH, the outputs do not change state, regardless of the data or clock input transitions.

Function Table

Inputs					Internal	Output	Function
$\overline{OE}$	$\overline{CLR}$	$\overline{EN}$	CP	D	Q	O	
H	X	L	↗	L	L	Z	High Z
H	X	L	↗	H	H	Z	High Z
H	L	X	X	X	L	Z	Clear
L	L	X	X	X	L	L	Clear
H	H	H	X	X	NC	Z	Hold
L	H	H	X	X	NC	NC	Hold
H	H	L	↗	L	L	Z	Load
H	H	L	↗	H	H	Z	Load
L	H	L	↗	L	L	L	Load
L	H	L	↗	H	H	H	Load

H = HIGH Voltage Level
L = LOW Voltage Level
X = Immaterial
Z = High Impedance
↗ = LOW-to-HIGH Transition
NC = No Change

Logic Diagram



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Please note that this diagram is provided only for the understanding of logic operations and should not be used to estimate propagation delays.

Absolute Maximum Ratings (Note 1)

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/Distributors for availability and specifications.

Supply Voltage (V_{CC})	−0.5V to 7.0V
DC Input Diode Current (I_{IK})	
$V_I = -0.5V$	−20 mA
$V_I = V_{CC} + 0.5V$	+20 mA
DC Input Voltage (V_I)	−0.5V to V_{CC} + 0.5V
DC Output Diode Current (I_{OK})	
$V_O = -0.5V$	−20 mA
$V_O = V_{CC} + 0.5V$	+20 mA
DC Output Voltage (V_O)	−0.5V to V_{CC} + 0.5V
DC Output Source or Sink Current (I_O)	±50 mA
DC V_{CC} or Ground Current per Output Pin (I_{CC} or I_{GND})	±50 mA
Storage Temperature (T_{STG})	−65°C to +150°C
Junction Temperature (T_J)	
CDIP	175°C
PDIP	140°C

Note 1: Absolute maximum ratings are those values beyond which damage to the device may occur. The databook specifications should be met, without exception, to ensure that the system design is reliable over its power supply, temperature, and output/input loading variables. National does not recommend operation of FACT™ circuits outside databook specifications.

Recommended Operating Conditions

Supply Voltage (V_{CC})	
'ACT	4.5V to 5.5V
Input Voltage (V_I)	0V to V_{CC}
Output Voltage (V_O)	0V to V_{CC}
Operating Temperature (T_A)	
74ACT	−40°C to +85°C
54ACT	−55°C to +125°C
Minimum Input Edge Rate ($\Delta V/\Delta t$)	
'ACT Devices	
V_{IN} from 0.8V to 2.0V	
V_{CC} @ 4.5V, 5.5V	125 mV/ns

DC Electrical Characteristics

Symbol	Parameter	V_{CC} (V)	74ACT $T_A = 25°C$		54ACT $T_A = -55°C$ to $+125°C$	74ACT $T_A = -40°C$ to $+85°C$	Units	Conditions
			Typ	Guaranteed Limits				
V_{IH}	Minimum High Level Input Voltage	4.5	1.5	2.0	2.0	2.0	V	$V_{OUT} = 0.1V$ or $V_{CC} - 0.1V$
		5.5	1.5	2.0	2.0	2.0		
V_{IL}	Maximum Low Level Input Voltage	4.5	1.5	0.8	0.8	0.8	V	$V_{OUT} = 0.1V$ or $V_{CC} - 0.1V$
		4.5	1.5	0.8	0.8	0.8		
V_{OH}	Minimum High Level	4.5	4.49	4.4	4.4	4.4	V	$I_{OUT} = -50\ \mu A$
			5.49	5.4	5.4	5.4		
		4.5		3.86	3.70	3.76	V	*$V_{IN} = V_{IL}$ or V_{IH} I_{OH} −24 mA
				4.86	4.70	4.76		−24 mA
V_{OL}	Maximum Low Level Output Voltage	4.5	0.001	0.1	0.1	0.1	V	$I_{OUT} = 50\ \mu A$
		5.5	0.001	0.1	0.1	0.1		
		4.5		0.36	0.50	0.44	V	*$V_{IN} = V_{IL}$ or V_{IH} I_{OL} 24 mA
		5.5		0.36	0.50	0.44		24 mA
I_{IN}	Maximum Input Leakage Current	5.5		±0.1	±1.0	±1.0	μA	$V_I = V_{CC}$, GND
I_{OZ}	Maximum TRI-STATE Current	5.5		±0.5	±10.0	±5.0	μA	$V_I = V_{IL}, V_{IH}$ $V_O = V_{CC}$, GND
I_{CCT}	Maximum I_{CC}/Input	5.5	0.6		1.6	1.5	mA	$V_I = V_{CC} - 2.1V$
I_{OLD}	†Minimum Dynamic Output Current	5.5			50	75	mA	$V_{OLD} = 1.65V$ Max
I_{OHD}		5.5			−50	−75	mA	$V_{OHD} = 3.85V$ Min
I_{CC}	Maximum Quiescent Supply Current	5.5		8.0	160	80	μA	$V_{IN} = V_{CC}$ or GND

*All outputs loaded; thresholds on input associated with output under test.

†Maximum test duration 2.0 ms, one output loaded at a time.

Note: I_{CC} limit for 54ACT @ 25°C is identical to 74ACT @ 25°C.

AC Electrical Characteristics

Symbol	Parameter	V_{CC}* (V)	74ACT $T_A = +25°C$, $C_L = 50pF$			54ACT $T_A = -55°C$ to $+125°C$, $C_L = 50$ pF		74ACT $T_A = -40°C$ to $+85°C$, $C_L = 50$ pF		Units
			Min	Typ	Max	Min	Max	Min	Max	
f_{max}	Maximum Clock Frequency	5.0	120	158		95		109		MHz
t_{PLH}	Propagation Delay CP to O_n	5.0	1.5	5.5	9.5	1.5	12.0	1.5	10.5	ns
t_{PHL}	Propagation Delay CP to O_n	5.0	2.0	5.5	9.5	1.5	12.0	1.5	10.5	ns
t_{PHL}	Propagation Delay $\overline{CLR}$ to O_n	5.0	2.5	8.0	13.5	1.5	18.0	2.0	15.5	ns
t_{PZH}	Output Enable Time $\overline{OE}$ to O_n	5.0	1.5	6.0	10.5	1.5	11.5	1.5	11.5	ns
t_{PZL}	Output Enable Time $\overline{OE}$ to O_n	5.0	2.0	6.5	11.0	1.5	12.0	1.5	12.0	ns
t_{PHZ}	Output Disable Time $\overline{OE}$ to O_n	5.0	1.5	6.5	11.0	1.5	13.5	1.5	12.0	ns
t_{PLZ}	Output Disable Time $\overline{OE}$ to O_n	5.0	1.5	6.0	10.5	1.5	12.0	1.5	11.5	ns

*Voltage Range 5.0 is 5.0V ±0.5V

AC Operating Requirements

Symbol	Parameter	V_{CC}* (V)	74ACT $T_A = +25°C$, $C_L = 50$ pF		54ACT $T_A = -55°C$ to $+125°C$, $C_L = 50$ pF	74ACT $T_A = -40°C$ to $+85°C$, $C_L = 50$ pF	Units
			Typ	Guaranteed Minimum			
t_s	Setup Time, HIGH or LOW D to CP	5.0	0.5	2.5	4.0	2.5	ns
t_h	Hold Time, HIGH or LOW D_n to CP	5.0	0	2.5	3.0	2.5	ns
t_s	Setup Time, HIGH or LOW $\overline{EN}$ to CP	5.0	0	2.0	4.0	2.5	ns
t_h	Hold Time, HIGH or LOW $\overline{EN}$ to CP	5.0	0	1.0	3.0	1.0	ns
t_w	CP Pulse Width HIGH or LOW	5.0	2.5	4.5	6.0	5.5	ns
t_w	$\overline{CLR}$ Pulse Width, LOW	5.0	3.0	5.5	7.0	5.5	ns
t_{rec}	$\overline{CLR}$ to CP Recovery Time	5.0	1.5	3.5	4.5	4.0	ns

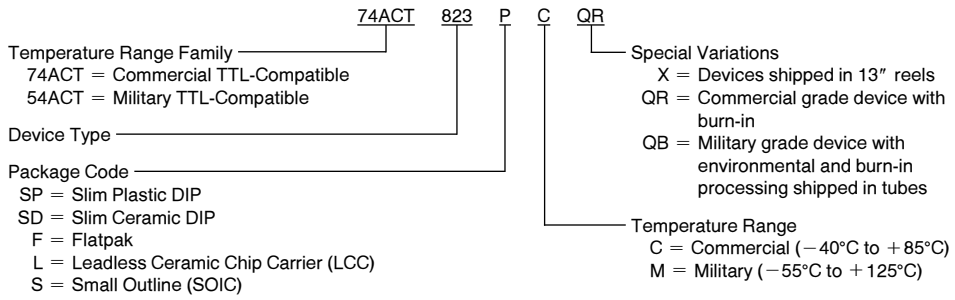
*Voltage Range 5.0 is 5.0V ±0.5V

Capacitance

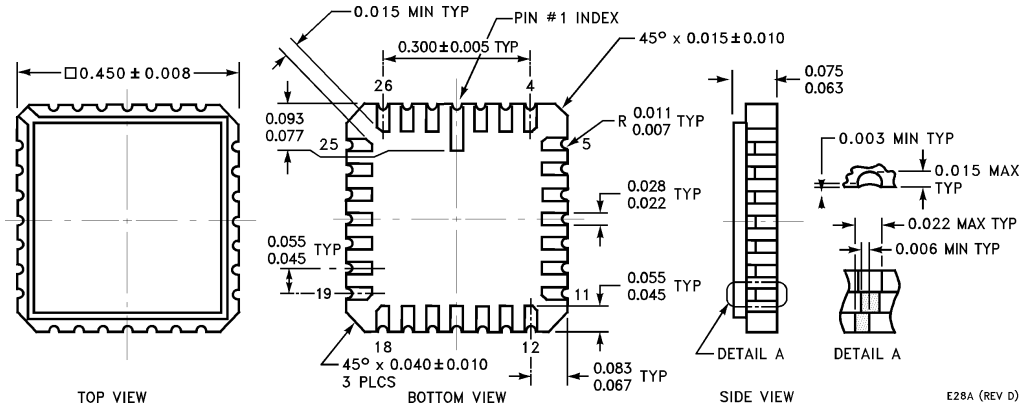
Symbol	Parameter	Typ	Units	Conditions
C_{IN}	Input Capacitance	4.5	pF	V_{CC} = OPEN
C_{PD}	Power Dissipation Capacitance	44	pF	V_{CC} = 5.0V

Ordering Information

The device number is used to form part of a simplified purchasing code where the package type and temperature range are defined as follows:

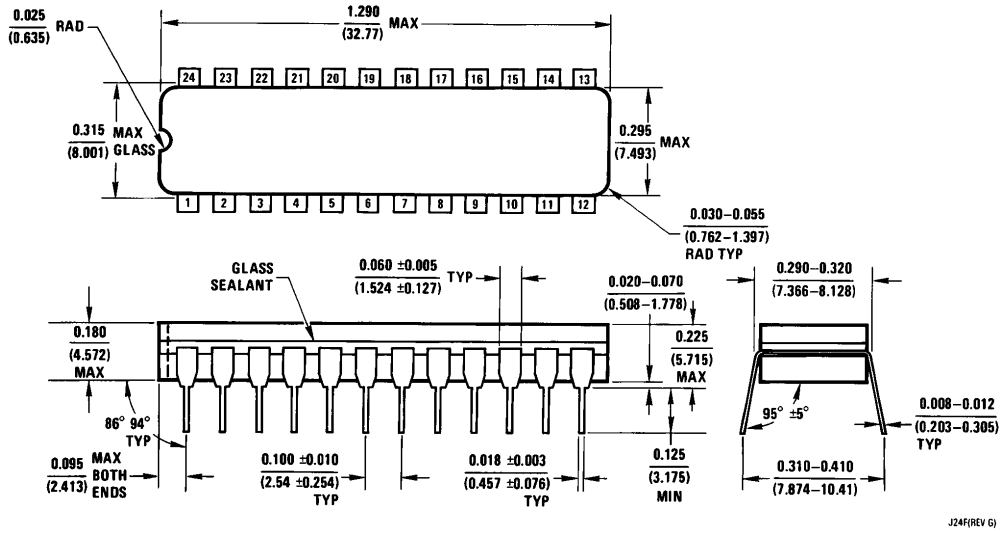


Physical Dimensions inches (millimeters)

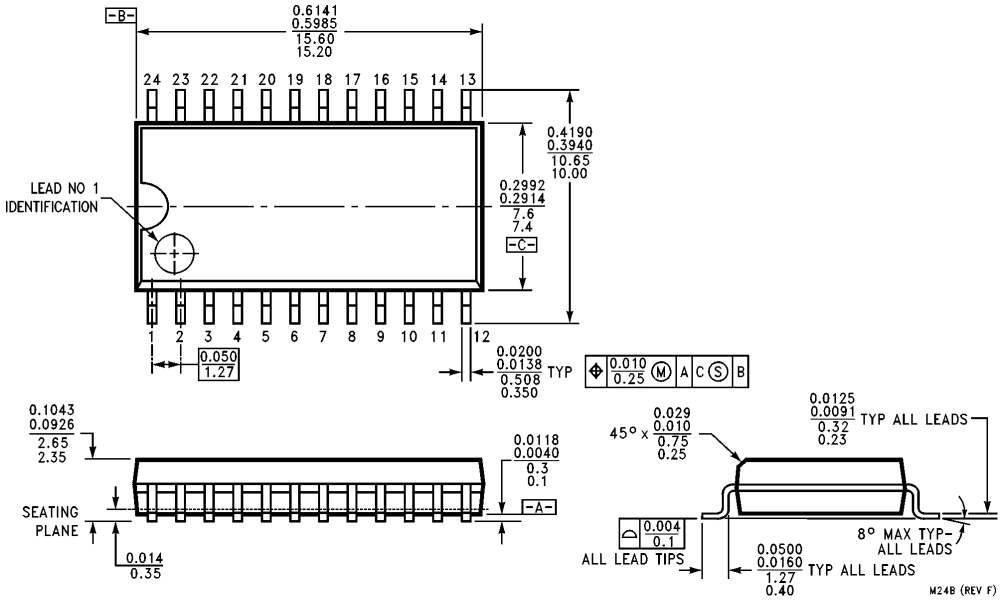


28 Terminal Ceramic Leadless Chip Carrier (L)
NS Package Number E28A

Physical Dimensions inches (millimeters) (Continued)

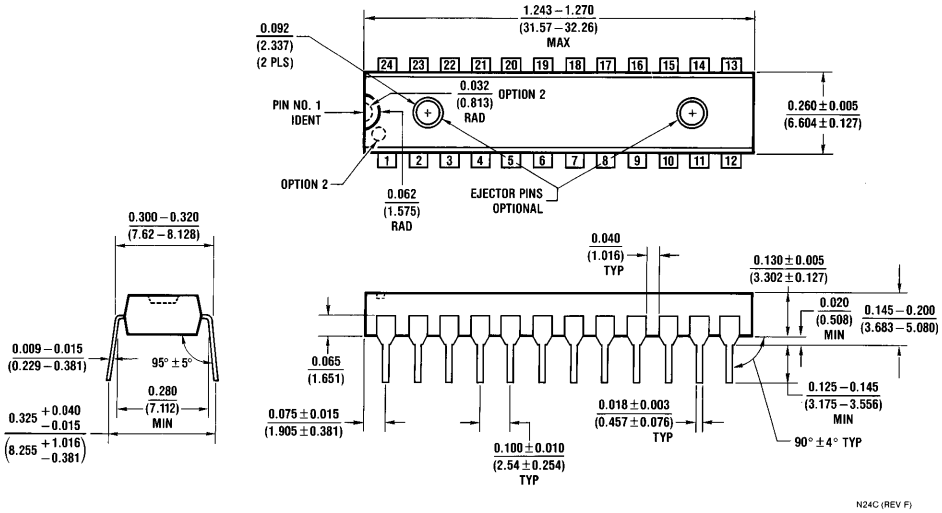


24 Lead Slim (0.300″ Wide) Ceramic Dual-In-Line (SD)
NS Package Number J24F



24 Lead Small Outline Integrated Circuit (S)
NS Package Number M24B

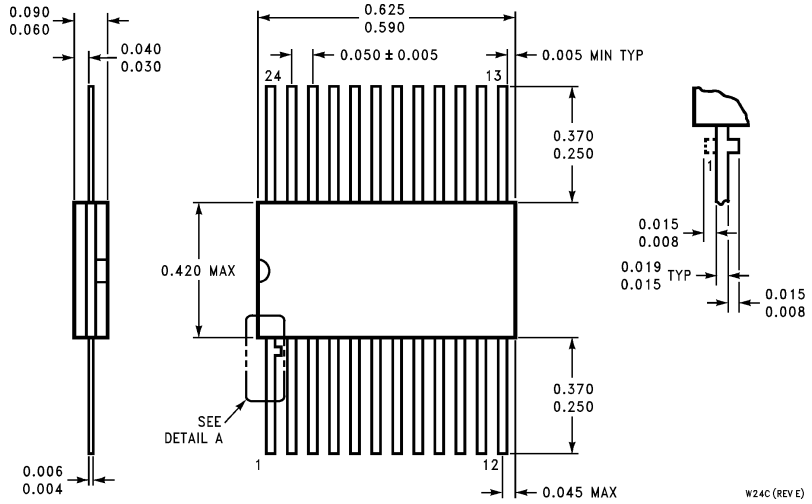
Physical Dimensions inches (millimeters) (Continued)



24 Lead Slim (0.300″ Wide) Plastic Dual-In-Line (SP)
NS Package Number N24C

Physical Dimensions inches (millimeters) (Continued)

Lit. # 114635



24 Lead Ceramic Flatpak (F)
NS Package Number W24C

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